

Notice of References Cited	Application/Control No. 09/708,722		Applicant(s)/Patent Under Reexamination JOURDAN ET AL.	
	Examiner Aimee J. Li		Art Unit 2183	Page 1 of 1

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*	B	US-6,418,530 B2	07-2002	Hsu et al.	712/237
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*	D	US-6,578,138 B1	06-2003	Kyker et al.	712/241
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NON-PATENT DOCUMENTS

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	U	Rotenberg, Eric; Bennet, Steve; Smith, James E. "A Trace Cache Microarchitecture and Evaluation". IEEE ©1999. Pages 111-120.
	V	Patel, Sanjay Jeram; Friendly, Daniel Holmes; Patt, Yale N. "Critical Issues Regarding the Trace Cache Fetch Mechanism". ©1997. Pages 1-33.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.